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of the real pattern window and predetermined pixels surrounding the noticed pixel of the real pattern window, outputting 1) a "0" difference value in a case where the obtained difference value is within a difference value obtained by shifting the design pattern window by one pixel or less, 2) a difference value obtained by subtracting the minimum value from the obtained difference value in a case where the obtained difference value is less than a minimum value of difference values obtained by shifting the design pattern window and 3) a difference value obtained by subtracting a maximum value of difference values which are obtained by shifting the design pattern window by one pixel or less from the obtained difference value in a case where the obtained difference value is lager than the maximum value, and performing the pattern inspection of the inspection object by comparing the outputted difference value with a threshold value set in advance.

According to a fourteenth aspect of the present invention, there is provided a pattern inspection device according to the eighth aspect, wherein the difference value is determined based on a lightness of pixels in the real pattern data and a lightness of pixels in the design pattern data.

According to a 15th aspect of the present invention, there is provided a method of manufacturing

The applicant refers to different embodiments as "aspects" (i.e., "eighth aspect"). This does not mean the applicant is referring to certain claims. On page 8 of specification filed on 03/29/00 is simply an embodiment and not a claim.

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